Advanced Machine Learning Applications in Big Data Analytics

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Deadline for manuscript submissions:
closed (20 February 2023)

Message from the Guest Editors

Dear colleagues,

With the development of computer technology and communication technology, various industries have collected a large amount of data in different forms, so-called big data. How to obtain valuable knowledge from these data is a very challenging task. Machine learning is such a direct and effective method for big data analytics. In recent years, a variety of advanced machine learning technologies have emerged, and they continue to play important roles in the era of big data.

This Special Issue is calling for high-quality papers in machine learning algorithms and applications in big data analytics. Topics include but are not limited to the following:

- Machine learning
- Data mining
- Data science
- Deep learning
- Classification
- Clustering
- Big data analytics
- Real-world applications

mdpi.com/si/104468

Special Issue

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Message from the Editor-in-Chief

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